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[Abstract] [PDF Full-Text (164 KB)] IEEE CNF

2 A method for storing fail bit maps in burn-in memory testers

Iseno, A.; Iguchi, Y.;

Electronic Design, Test and Applications, 2002. Proceedings. The First IEEE International Workshop on , 2002

Page(s): 142 -145

[Abstract] [PDF Full-Text (278 KB)] **IEEE CNF**

3 Simulating package behavior under power dissipation using uniform thermal loading

Wakil, J.A.; Ho, P.S.;

Advanced Packaging, IEEE Transactions on [see also Components, Packaging and Manufacturing Technology, Part B: Advanced Packaging, IEEE Transactions on], Volume: 24 Issue: 1, Feb 2001 Page(s): 60 -65

[Abstract] [PDF Full-Text (112 KB)] IEEE JNL

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